

Silicon Diode Array

1N5768

60V/300mA

DATASHEET

OEM – Fairchild

Source: Fairchild Databook 1978

1N5768 • 1N5770 • 1N5772 • 1N5774

MONOLITHIC AIR ISOLATED DIODE ARRAYS

- BV... 60 V @ 10 μ A
- I_R... 100 nA @ 40 V
- V_R... 1 V @ 100 mA

ABSOLUTE MAXIMUM RATINGS (Note 1)

Temperatures

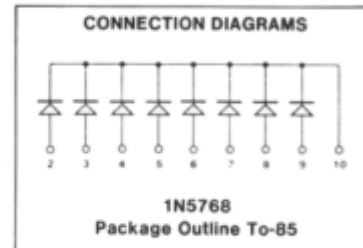
Storage Temperature Range	-65°C to +200°C
Junction Operating Temperature Range	-65°C to +200°C

Maximum Power Dissipation

Maximum Total Dissipation at T _A = 25°C	500 mW
Linear Derating Factor	4.0 mW / °C above 25°C

Maximum Currents

I _O	Average Rectified Current (each diode)	300 mA
	Linear Derating Factor	2.4 mA / °C above 25°C
I _{FSM}	Peak Forward Surge Current Pulse Width = 8.3 ms	500 mA



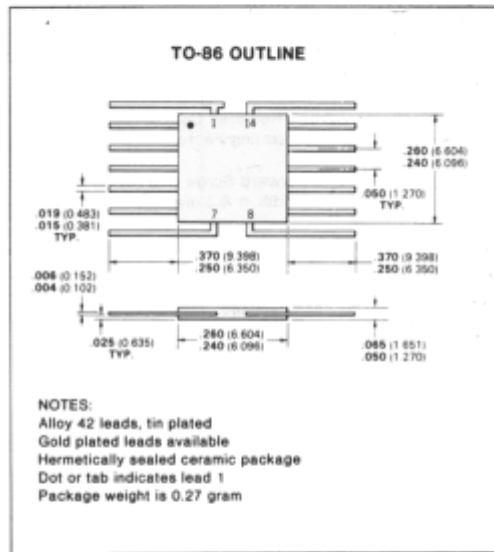
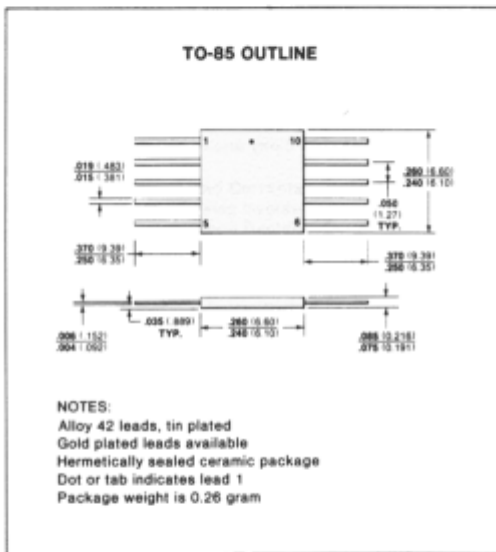
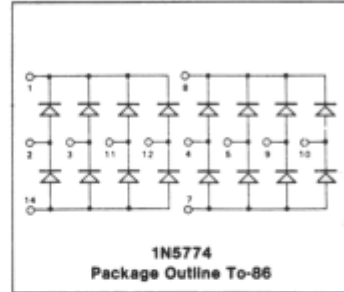
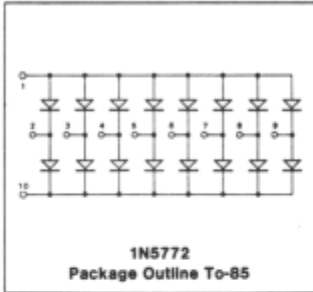
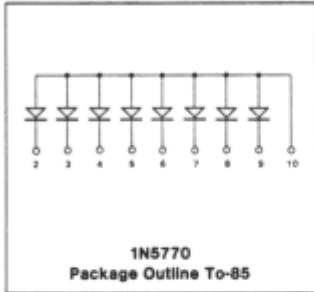
ELECTRICAL CHARACTERISTICS (25°C Ambient Temperature unless otherwise noted)

SYMBOL	CHARACTERISTIC	MIN	MAX	UNITS	TEST CONDITIONS
BV	Breakdown Voltage	60		V	I _R = 10 μ A, Pulse Width = 100 μ s, Duty Cycle < 20%
V _F	Forward Voltage		1.0 1.5	V	I _F = 100 mA I _F = 500 mA, Pulse Width = 300 ns, Duty Cycle = 2%
V _{FX}	Forward Voltage		1.0	V	I _F = 25 mA; I _F = 25 mA for each of the other Diodes in the Test Section (Note 3)
V _{FM}	Peak Forward Voltage		5.0	V	I _F = 500 mA, Pulse Width = 150 ns, Duty Cycle \leq 2%
I _R	Reverse Current		100 50	nA μ A	V _R = 40 V V _R = 40 V, T _A = +150°C
I _{RX}	Reverse Current		10	μ A	V _R = 40 V, I _F = 25 mA for each of the other Diodes in the Test Section (Note 3)
I _{Ri}	Isolation Current 1N5772, 1N5774		0.8	μ A	V _R = 40 V (Note 4)
C	Pin-to-Pin Capacitance (Note 2) 1N5768 1N5770, 1N5772, 1N5774		4.0 8.0	pF pF	V _R = 0 V, f = 1.0 MHz V _R = 0 V, f = 1.0 MHz
t _{fr}	Forward Recovery Time (Note 5)		40	ns	I _F = 500 mA, R _S = 10 Ω , V _{fr} = 1.8 V, t _r = 15 ns Max
t _{rr}	Reverse Recovery Time (Note 5)		20	ns	I _F = 200 mA, I _r = 200 mA, R _L = 100 Ω , I _{rr} = 20 mA

NOTES:

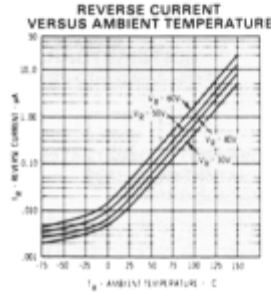
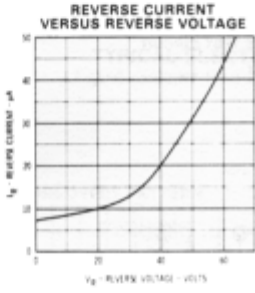
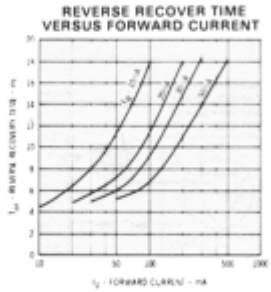
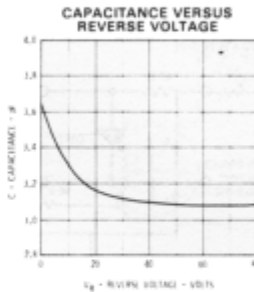
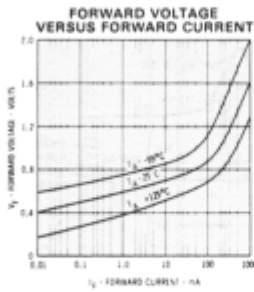
- The maximum ratings are limiting values above which life or satisfactory performance may be impaired.
- This parameter is the total pin-to-pin capacitance measured across each diode. This does not necessarily represent actual diode capacitance since other diode interconnections can contribute additional capacitance.
- Each common anode section and/or common cathode section tested separately.
- The isolation current shall be measured between any two interconnect pins of adjacent parallel sets of diodes with all other pins open circuited.
- For Product Family characteristic curves and Test Circuits, refer to Chapter 4, D15.

FAIRCHILD • DIODE ARRAYS



CURVE SET NUMBER D15
AIR-ISOLATED MONOLITHIC DIODE ARRAY

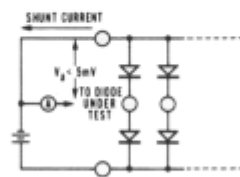
TYPICAL ELECTRICAL CHARACTERISTIC CURVES
 AT 25°C AMBIENT TEMPERATURE UNLESS OTHERWISE NOTED



TEST CIRCUITS

To measure reverse current of an individual diode, the following test circuits are used:

COMMON CATHODE DIODES



COMMON ANODE DIODES

